

Application/Control No.	Applicant(s)/Patent u Reexamination	Applicant(s)/Patent under Reexamination	
09/922,995	RUBINSTEIN ET AL		
Examiner	Art Unit		
CHLIONIC T HO	2664		

SEARCHED			
Class	Subclass	Date	Examiner
370	2417	11/21/05	CH CH
370	536:		
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340	533		
340	538		
340	541		
370	4421		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	241	11/21/05	CH 1
370	536		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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STN IEEE	↓ ↓	-	
Consulting with	11/22/05	C14	
Wellington Chin SPE AU 2664			
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Partel Ajik	,		
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Primary Examiner. Class 370/241			
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Search Notes

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09/922,995		RUBINSTEIN	LET AL.
Examiner		Art Unit	
CHUONG T HO		2664	

SEARCHED			
Class	Subclass	Date	Examiner
455	522	11/21/05	СH
713	300		
713	310		
375	257		
340	538,11		
340	870.18		
340	870.19		
340	870.31		
709	224		
370	260		
370	2415		
370	242 %		
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
37C	534	11/21/05	0H
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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